HM5164405F Series
HM5165405F Series

64 M EDO DRAM (16-Mword × 4-bit)
8 k Refresh/4 k Refresh

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Description

The Hitachi HM5164405F Series, HM5165405F Series are 64M-bit dynamic RAMs organized as 16,777,216-word × 4-bit. They have realized high performance and low power by employing CMOS process technology. HM5164405F Series, HM5165405F Series offer Extended Data Out (EDO) Page Mode as a high speed access mode. They have the package variation of standard 32-pin plastic SOJ and standard 32-pin plastic TSOPII.

Features

- Single 3.3 V supply: 3.3 V ± 0.3 V
- Access time: 50 ns/60 ns (max)
- Power dissipation
    — Active: 396 mW/360 mW (max) (HM5164405F Series)
        : 468 mW/396 mW (max) (HM5165405F Series)
    — Standby : 1.8 mW (max) (CMOS interface)
        : 1.1 mW (max) (L-version)
- EDO page mode capability
- Refresh cycles
    — $\overline{RAS}$-only refresh
        8192 cycles /64 ms (HM5164405F, HM5164405FL)
        4096 cycles /64 ms (HM5165405F, HM5165405FL)
    — CBR/Hidden refresh
        4096 cycles /64 ms (HM5164405F, HM5164405FL, HM5165405F, HM5165405FL)
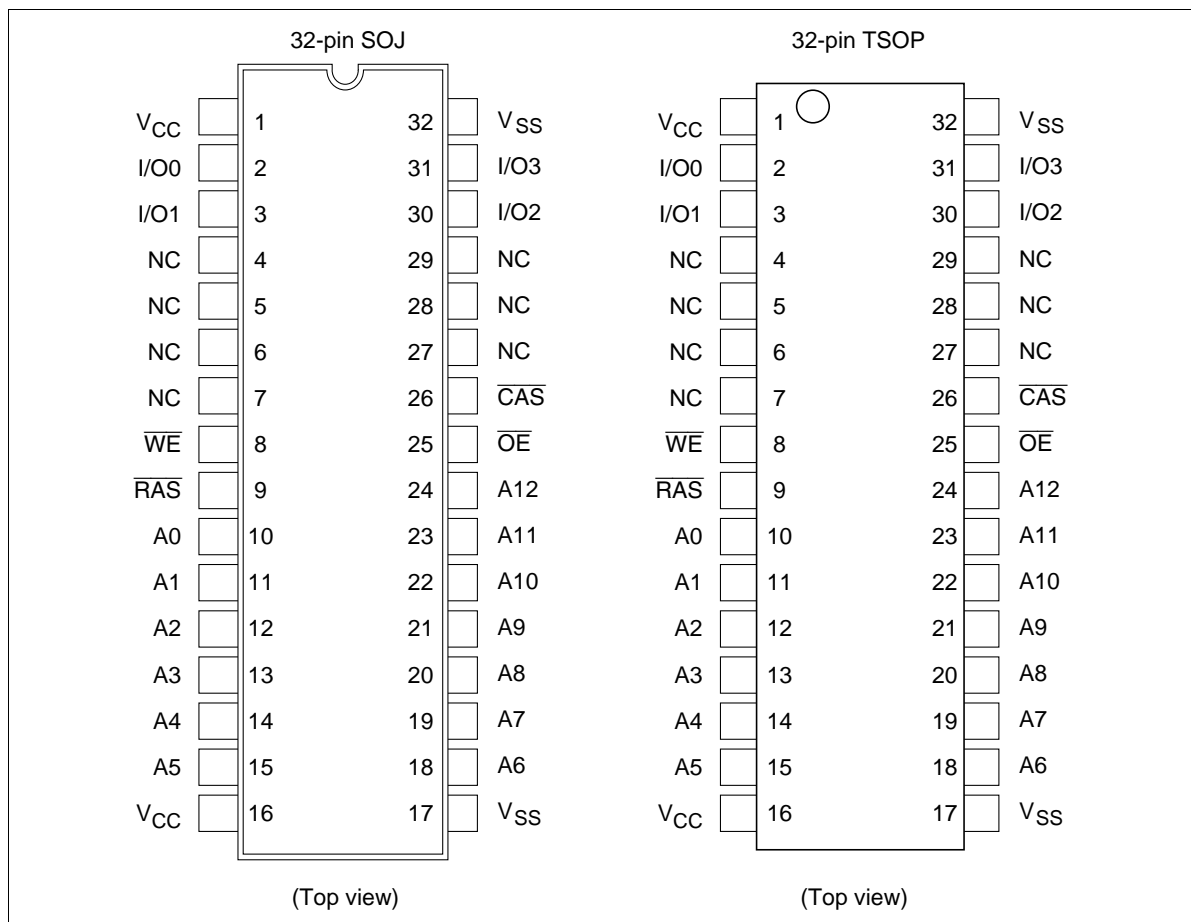
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- 4 variations of refresh
  - $\overline{\text{RAS}}$-only refresh
  - $\overline{\text{CAS}}$-before-$\overline{\text{RAS}}$ refresh
  - Hidden refresh
  - Self refresh (L-version)
- Battery backup operation (L-version)

Ordering Information

Type No.	Access time	Package
HM5164405FJ-5 HM5164405FJ-6	50 ns 60 ns	400-mil 32-pin plastic SOJ (CP-32DC)
HM5164405FLJ-5 HM5164405FLJ-6	50 ns 60 ns	
HM5165405FJ-5 HM5165405FJ-6	50 ns 60 ns	
HM5165405FLJ-5 HM5165405FLJ-6	50 ns 60 ns	
HM5164405FTT-5 HM5164405FTT-6	50 ns 60 ns	400-mil 32-pin plastic TSOP II (TTP-32DC)
HM5164405FLTT-5 HM5164405FLTT-6	50 ns 60 ns	
HM5165405FTT-5 HM5165405FTT-6	50 ns 60 ns	
HM5165405FLTT-5 HM5165405FLTT-6	50 ns 60 ns	

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Pin Arrangement (HM5164405F Series)

32-pin SOJ		32-pin TSOP	
V_{CC}	1 — 32	V_{SS}	V_{CC} — 1 — 32 — V_{SS}

32-pin SOJ (Top view)

Left	Pin	Pin	Right
V_{CC}	1	32	V_{SS}
I/O0	2	31	I/O3
I/O1	3	30	I/O2
NC	4	29	NC
NC	5	28	NC
NC	6	27	NC
NC	7	26	$\overline{CAS}$
$\overline{WE}$	8	25	$\overline{OE}$
$\overline{RAS}$	9	24	A12
A0	10	23	A11
A1	11	22	A10
A2	12	21	A9
A3	13	20	A8
A4	14	19	A7
A5	15	18	A6
V_{CC}	16	17	V_{SS}

32-pin TSOP (Top view)

Left	Pin	Pin	Right
V_{CC}	1	32	V_{SS}
I/O0	2	31	I/O3
I/O1	3	30	I/O2
NC	4	29	NC
NC	5	28	NC
NC	6	27	NC
NC	7	26	$\overline{CAS}$
$\overline{WE}$	8	25	$\overline{OE}$
$\overline{RAS}$	9	24	A12
A0	10	23	A11
A1	11	22	A10
A2	12	21	A9
A3	13	20	A8
A4	14	19	A7
A5	15	18	A6
V_{CC}	16	17	V_{SS}

Pin Description

Pin name	Function
A0 to A12	Address input — Row/Refresh address A0 to A12 — Column address A0 to A10
I/O0 to I/O3	Data input/output
$\overline{RAS}$	Row address strobe
$\overline{CAS}$	Column address strobe
$\overline{WE}$	Write enable
$\overline{OE}$	Output enable
V_{CC}	Power supply
V_{SS}	Ground
NC	No connection

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Pin Arrangement (HM5165405F Series)

	32-pin SOJ			32-pin TSOP	
V_{CC}	1	32 V_{SS}	V_{CC}	1	32 V_{SS}
I/O0	2	31 I/O3	I/O0	2	31 I/O3
I/O1	3	30 I/O2	I/O1	3	30 I/O2
NC	4	29 NC	NC	4	29 NC
NC	5	28 NC	NC	5	28 NC
NC	6	27 NC	NC	6	27 NC
NC	7	26 $\overline{CAS}$	NC	7	26 $\overline{CAS}$
$\overline{WE}$	8	25 $\overline{OE}$	$\overline{WE}$	8	25 $\overline{OE}$
$\overline{RAS}$	9	24 NC	$\overline{RAS}$	9	24 NC
A0	10	23 A11	A0	10	23 A11
A1	11	22 A10	A1	11	22 A10
A2	12	21 A9	A2	12	21 A9
A3	13	20 A8	A3	13	20 A8
A4	14	19 A7	A4	14	19 A7
A5	15	18 A6	A5	15	18 A6
V_{CC}	16	17 V_{SS}	V_{CC}	16	17 V_{SS}
	(Top view)			(Top view)	
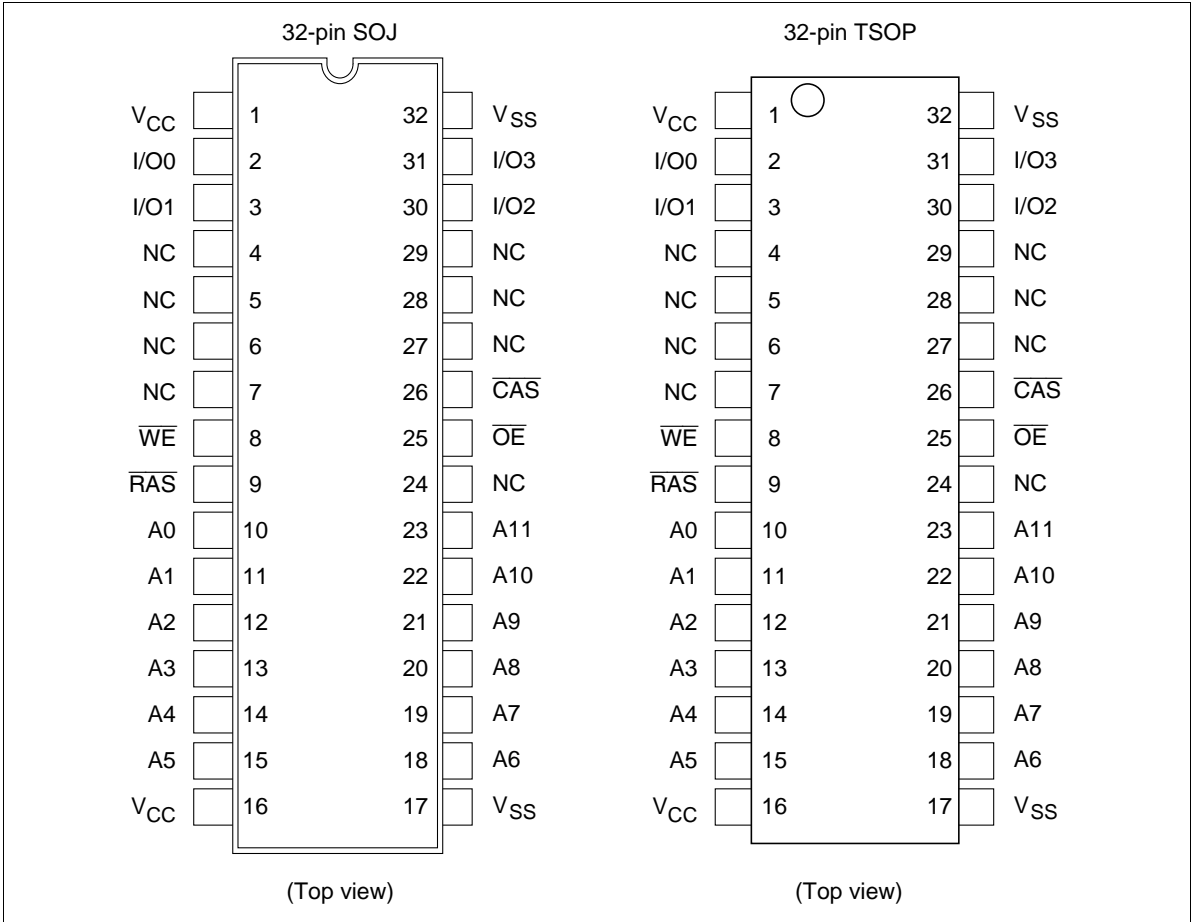
Pin Description

Pin name	Function
A0 to A11	Address input — Row/Refresh address A0 to A11 — Column address A0 to A11
I/O0 to I/O3	Data input/output
$\overline{RAS}$	Row address strobe
$\overline{CAS}$	Column address strobe
$\overline{WE}$	Write enable
$\overline{OE}$	Output enable
V_{CC}	Power supply
V_{SS}	Ground
NC	No connection

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Block Diagram (HM5164405F Series)

HM5164405F Series, HM5165405F Series
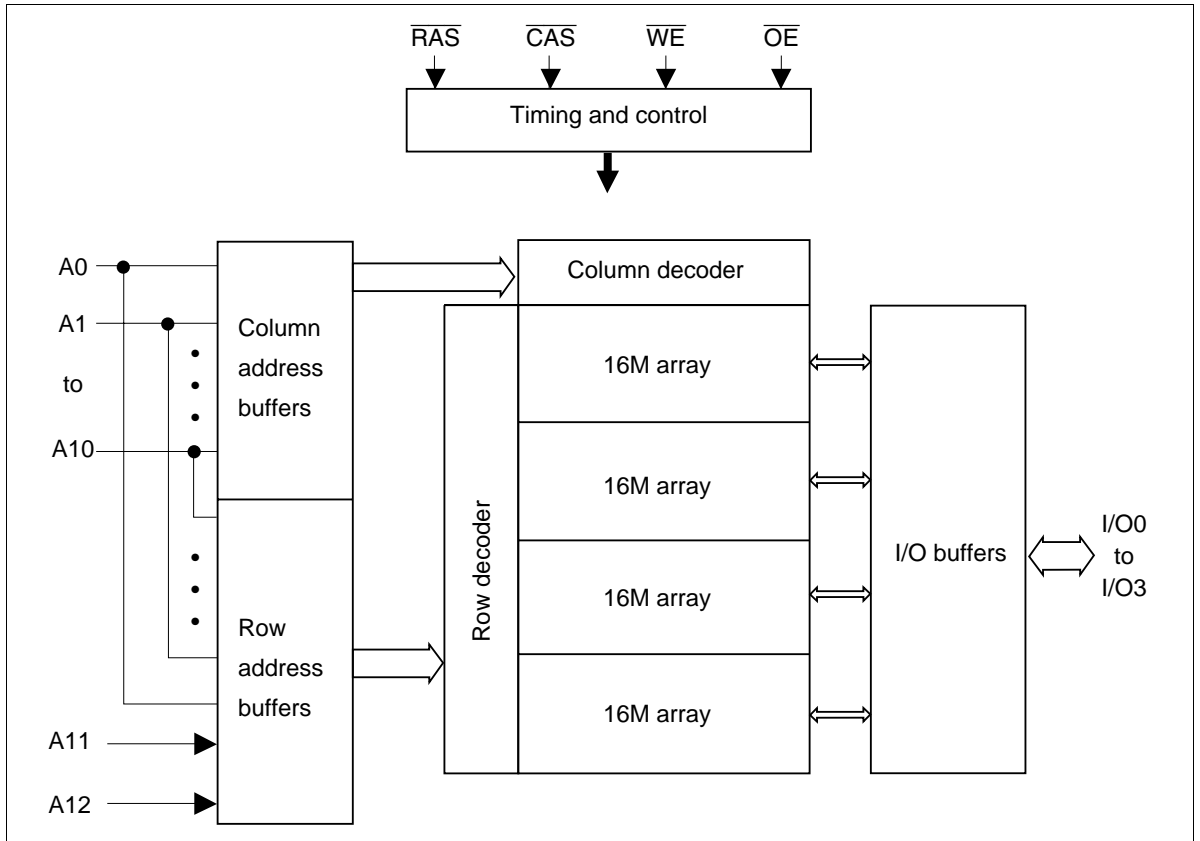
Block Diagram (HM5165405F Series)

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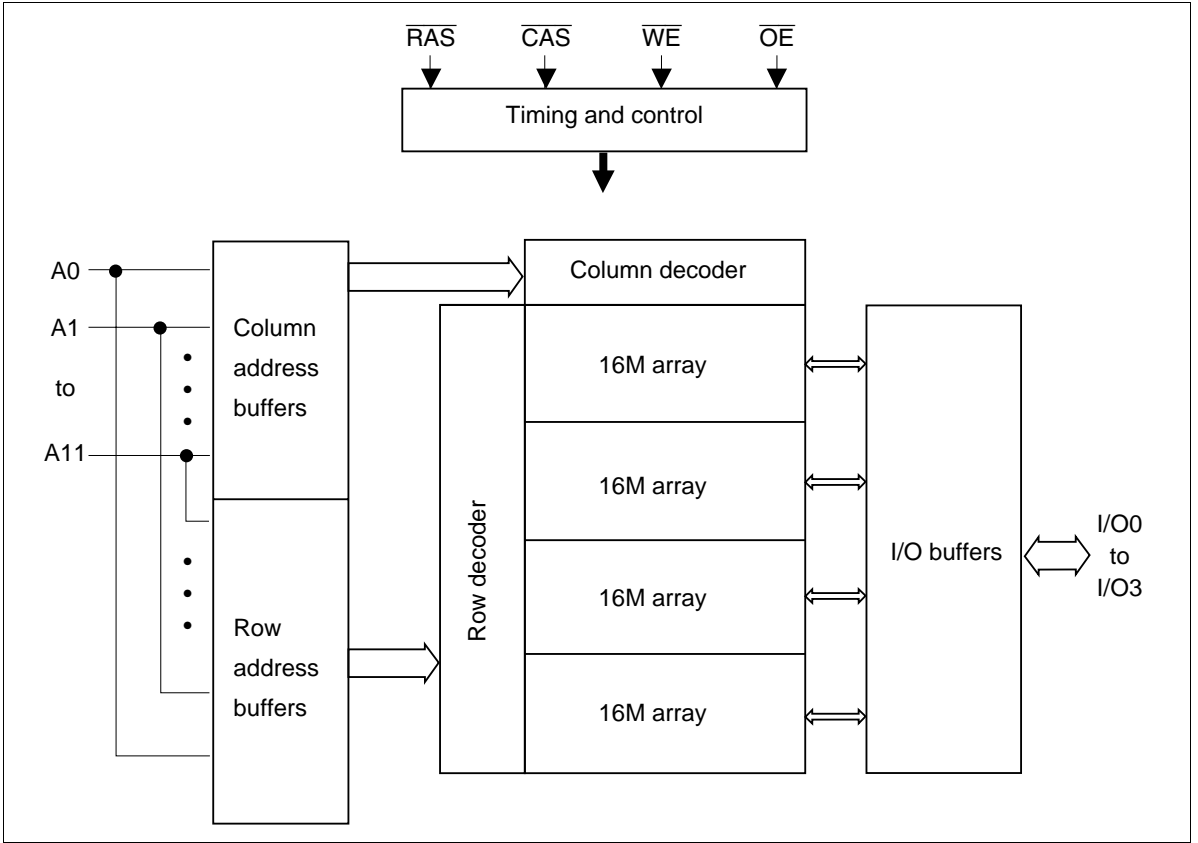
Operation Table

$\overline{RAS}$	$\overline{CAS}$	$\overline{WE}$	$\overline{OE}$	I/O 0 to I/O 3	Operation
H	×	×	×	High-Z	Standby
L	L	H	L	Dout	Read cycle
L	L	L*²	×	Din	Early write cycle
L	L	L*²	H	Din	Delayed write cycle
L	L	H to L	L to H	Dout/Din	Read-modify-write cycle
L	H	×	×	High-Z	$\overline{RAS}$-only refresh cycle
H to L	L	H	×	High-Z	$\overline{CAS}$-before-$\overline{RAS}$ refresh cycle or Self refresh cycle (L-version)
L	L	H	H	High-Z	Read cycle (Output disabled)

Notes: 1. H: V_{IH} (inactive), L: V_{IL} (active), ×: V_{IH} or V_{IL}

2. $t_{WCS} \geq 0$ ns: Early write cycle

$t_{WCS} < 0$ ns: Delayed write cycle

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Terminal voltage on any pin relative to V_{SS}	V_T	–0.5 to V_{CC} + 0.5 ($\leq$ 4.6 V (max))	V
Power supply voltage relative to V_{SS}	V_{CC}	–0.5 to +4.6	V
Short circuit output current	Iout	50	mA
Power dissipation	P_T	1.0	W
Storage temperature	Tstg	–55 to +125	°C

DC Operating Conditions

Parameter	Symbol	Min	Typ	Max	Unit	Notes
Supply voltage	V_{CC}	3.0	3.3	3.6	V	1, 2
	V_{SS}	0	0	0	V	2
Input high voltage	V_{IH}	2.0	—	V_{CC} + 0.3	V	1
Input low voltage	V_{IL}	–0.3	—	0.8	V	1
Ambient temperature range	Ta	0	—	70	°C	

Notes: 1. All voltage referred to V_{SS}.

2. The supply voltage with all V_{CC} pins must be on the same level. The supply voltage with all V_{SS} pins must be on the same level.

DC Characteristics (HM5164405F Series)

Parameter	Symbol	HM5164405F				Unit	Test conditions
		-5		**-6**			
		Min	Max	Min	Max		
Operating current*[1], *[2]	I_{CC1}	—	110	—	100	mA	t_{RC} = min
Standby current	I_{CC2}	—	2	—	2	mA	TTL interface $\overline{RAS}$, $\overline{CAS}$ = V_{IH} Dout = High-Z
		—	0.5	—	0.5	mA	CMOS interface $\overline{RAS}$, $\overline{CAS}$ ≥ V_{CC} – 0.2 V Dout = High-Z
Standby current (L-version)	I_{CC2}	—	300	—	300	µA	CMOS interface $\overline{RAS}$, $\overline{CAS}$ ≥ V_{CC} – 0.2 V Dout = High-Z
$\overline{RAS}$-only refresh current*[2]	I_{CC3}	—	110	—	100	mA	t_{RC} = min
Standby current*[1]	I_{CC5}	—	5	—	5	mA	$\overline{RAS}$ = V_{IH}, $\overline{CAS}$ = V_{IL} Dout = enable
$\overline{CAS}$-before-$\overline{RAS}$ refresh current	I_{CC6}	—	110	—	100	mA	t_{RC} = min
EDO page mode current*[1], *[3]	I_{CC7}	—	110	—	100	mA	$\overline{RAS}$ = V_{IL}, $\overline{CAS}$ cycle, t_{HPC} = t_{HPC} min
Battery backup current*[4] (Standby with CBR refresh) (L-version)	I_{CC10}	—	1.2	—	1.2	mA	CMOS interface Dout = High-Z CBR refresh: t_{RC} = 15.6 µs t_{RAS} ≤ 0.3 µs
Self refresh mode current (L-version)	I_{CC11}	—	500	—	500	µA	CMOS interface $\overline{RAS}$, $\overline{CAS}$ ≤ 0.2 V Dout = High-Z
Input leakage current	I_{LI}	–5	5	–5	5	µA	0 V ≤ Vin ≤ V_{CC} + 0.3 V
Output leakage current	I_{LO}	–5	5	–5	5	µA	0 V ≤ Vout ≤ V_{CC} Dout = disable
Output high voltage	V_{OH}	2.4	V_{CC}	2.4	V_{CC}	V	High Iout = –2 mA
Output low voltage	V_{OL}	0	0.4	0	0.4	V	Low Iout = 2 mA

Notes: 1. I_{CC} depends on output load condition when the device is selected. I_{CC} max is specified at the output open condition.

2. Address can be changed once or less while $\overline{RAS}$ = V_{IL}.

3. Measured with one sequential address change per EDO cycle, t_{HPC}.

4. V_{IH} ≥ V_{CC} – 0.2 V, 0 V ≤ V_{IL} ≤ 0.2 V.

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DC Characteristics (HM5165405F Series)

| Parameter | Symbol | HM5165405F | | | | Unit | Test conditions |
| | | -5 | | -6 | | | |
		Min	Max	Min	Max		
Operating current*[1, 2]	I_{CC1}	—	130	—	110	mA	t_{RC} = min
Standby current	I_{CC2}	—	2	—	2	mA	TTL interface $\overline{RAS}$, $\overline{CAS}$ = V_{IH} Dout = High-Z
		—	0.5	—	0.5	mA	CMOS interface $\overline{RAS}$, $\overline{CAS} \geq V_{CC} - 0.2$ V Dout = High-Z
Standby current (L-version)	I_{CC2}	—	300	—	300	μA	CMOS interface $\overline{RAS}$, $\overline{CAS} \geq V_{CC} - 0.2$ V Dout = High-Z
$\overline{RAS}$-only refresh current*[2]	I_{CC3}	—	130	—	110	mA	t_{RC} = min
Standby current*[1]	I_{CC5}	—	5	—	5	mA	$\overline{RAS} = V_{IH}$, $\overline{CAS} = V_{IL}$ Dout = enable
$\overline{CAS}$-before-$\overline{RAS}$ refresh current	I_{CC6}	—	130	—	110	mA	t_{RC} = min
EDO page mode current*[1, 3]	I_{CC7}	—	110	—	100	mA	$\overline{RAS} = V_{IL}$, $\overline{CAS}$ cycle, $t_{HPC} = t_{HPC}$ min
Battery backup current*[4] (Standby with CBR refresh) (L-version)	I_{CC10}	—	1.2	—	1.2	mA	CMOS interface Dout = High-Z CBR refresh: t_{RC} = 15.6 μs $t_{RAS} \leq 0.3$ μs
Self refresh mode current (L-version)	I_{CC11}	—	500	—	500	μA	CMOS interface $\overline{RAS}$, $\overline{CAS} \leq 0.2$ V Dout = High-Z
Input leakage current	I_{LI}	–5	5	–5	5	μA	0 V $\leq$ Vin $\leq V_{CC}$ + 0.3 V
Output leakage current	I_{LO}	–5	5	–5	5	μA	0 V $\leq$ Vout $\leq V_{CC}$ Dout = disable
Output high voltage	V_{OH}	2.4	V_{CC}	2.4	V_{CC}	V	High Iout = –2 mA
Output low voltage	V_{OL}	0	0.4	0	0.4	V	Low Iout = 2 mA

Notes: 1. I_{CC} depends on output load condition when the device is selected. I_{CC} max is specified at the output open condition.

2. Address can be changed once or less while $\overline{RAS} = V_{IL}$.

3. Measured with one sequential address change per EDO cycle, t_{HPC}.

4. $V_{IH} \geq V_{CC} - 0.2$ V, 0 V $\leq V_{IL} \leq 0.2$ V.

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Capacitance (Ta = 25˚C, $V_{CC} = 3.3$ V $\pm$ 0.3 V)

Parameter	Symbol	Typ	Max	Unit	Notes
Input capacitance (Address)	C_{I1}	—	5	pF	1
Input capacitance (Clocks)	C_{I2}	—	7	pF	1
Output capacitance (Data-in, Data-out)	$C_{I/O}$	—	7	pF	1, 2

Notes : 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.

2. $\overline{RAS}$ and $\overline{CAS}$ = V_{IH} to disable Dout.

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AC Characteristics (Ta = 0 to +70°C, V_{CC} = 3.3 V ± 0.3 V, V_{SS} = 0 V) [1], [2], [19]

Test Conditions

- Input rise and fall time: 2 ns
- Input pulse levels: V_{IL} = 0 V, V_{IH} = 3.0 V
- Input timing reference levels: 0.8 V, 2.0 V
- Output timing reference levels: 0.8 V, 2.0 V
- Output load: 1 TTL gate + C_L (100 pF) (Including scope and jig)

Read, Write, Read-Modify-Write and Refresh Cycles (Common parameters)

Parameter	Symbol	HM5164405F/HM5165405F				Unit	Notes
		-5		-6			
		Min	Max	Min	Max		
Random read or write cycle time	t_{RC}	84	—	104	—	ns	
$\overline{RAS}$ precharge time	t_{RP}	30	—	40	—	ns	
$\overline{CAS}$ precharge time	t_{CP}	8	—	10	—	ns	
$\overline{RAS}$ pulse width	t_{RAS}	50	10000	60	10000	ns	
$\overline{CAS}$ pulse width	t_{CAS}	8	10000	10	10000	ns	
Row address setup time	t_{ASR}	0	—	0	—	ns	
Row address hold time	t_{RAH}	8	—	10	—	ns	
Column address setup time	t_{ASC}	0	—	0	—	ns	
Column address hold time	t_{CAH}	8	—	10	—	ns	
$\overline{RAS}$ to $\overline{CAS}$ delay time	t_{RCD}	12	37	14	45	ns	3
$\overline{RAS}$ to column address delay time	t_{RAD}	10	25	12	30	ns	4
$\overline{RAS}$ hold time	t_{RSH}	13	—	15	—	ns	
$\overline{CAS}$ hold time	t_{CSH}	35	—	40	—	ns	
$\overline{CAS}$ to $\overline{RAS}$ precharge time	t_{CRP}	5	—	5	—	ns	
$\overline{OE}$ to Din delay time	t_{OED}	13	—	15	—	ns	5
$\overline{OE}$ delay time from Din	t_{DZO}	0	—	0	—	ns	6
$\overline{CAS}$ delay time from Din	t_{DZC}	0	—	0	—	ns	6
Transition time (rise and fall)	t_T	2	50	2	50	ns	7

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Read Cycle

Parameter	Symbol	HM5164405F/HM5165405F				Unit	Notes
		-5		**-6**			
		Min	**Max**	**Min**	**Max**		
Access time from $\overline{RAS}$	t_{RAC}	—	50	—	60	ns	8, 9
Access time from $\overline{CAS}$	t_{CAC}	—	13	—	15	ns	9, 10, 17
Access time from address	t_{AA}	—	25	—	30	ns	9, 11, 17
Access time from $\overline{OE}$	t_{OEA}	—	13	—	15	ns	9
Read command setup time	t_{RCS}	0	—	0	—	ns	
Read command hold time to $\overline{CAS}$	t_{RCH}	0	—	0	—	ns	12
Read command hold time from $\overline{RAS}$	t_{RCHR}	50	—	60	—	ns	
Read command hold time to $\overline{RAS}$	t_{RRH}	0	—	0	—	ns	12
Column address to $\overline{RAS}$ lead time	t_{RAL}	25	—	30	—	ns	
Column address to $\overline{CAS}$ lead time	t_{CAL}	15	—	18	—	ns	
$\overline{CAS}$ to output in low-Z	t_{CLZ}	0	—	0	—	ns	
Output data hold time	t_{OH}	3	—	3	—	ns	21
Output data hold time from $\overline{OE}$	t_{OHO}	3	—	3	—	ns	
Output buffer turn-off time	t_{OFF}	—	13	—	15	ns	13, 21
Output buffer turn-off to $\overline{OE}$	t_{OEZ}	—	13	—	15	ns	13
$\overline{CAS}$ to Din delay time	t_{CDD}	13	—	15	—	ns	5
Output data hold time from $\overline{RAS}$	t_{OHR}	3	—	3	—	ns	21
Output buffer turn-off to $\overline{RAS}$	t_{OFR}	—	13	—	15	ns	13, 21
Output buffer turn-off to $\overline{WE}$	t_{WEZ}	—	13	—	15	ns	13
$\overline{WE}$ to Din delay time	t_{WED}	13	—	15	—	ns	
$\overline{RAS}$ to Din delay time	t_{RDD}	13	—	15	—	ns	

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Write Cycle

| Parameter | Symbol | HM5164405F/HM5165405F | | | | Unit | Notes |
| | | -5 | | -6 | | | |
		Min	Max	Min	Max		
Write command setup time	t_{WCS}	0	—	0	—	ns	14
Write command hold time	t_{WCH}	8	—	10	—	ns	
Write command pulse width	t_{WP}	8	—	10	—	ns	
Write command to $\overline{RAS}$ lead time	t_{RWL}	13	—	15	—	ns	
Write command to $\overline{CAS}$ lead time	t_{CWL}	8	—	10	—	ns	
Data-in setup time	t_{DS}	0	—	0	—	ns	15
Data-in hold time	t_{DH}	8	—	10	—	ns	15

Read-Modify-Write Cycle

| Parameter | Symbol | HM5164405F/HM5165405F | | | | Unit | Notes |
| | | -5 | | -6 | | | |
		Min	Max	Min	Max		
Read-modify-write cycle time	t_{RWC}	116	—	140	—	ns	
$\overline{RAS}$ to $\overline{WE}$ delay time	t_{RWD}	67	—	79	—	ns	14
$\overline{CAS}$ to $\overline{WE}$ delay time	t_{CWD}	30	—	34	—	ns	14
Column address to $\overline{WE}$ delay time	t_{AWD}	42	—	49	—	ns	14
$\overline{OE}$ hold time from $\overline{WE}$	t_{OEH}	13	—	15	—	ns	

Refresh Cycle

| Parameter | Symbol | HM5164405F/HM5165405F | | | | Unit | Notes |
| | | -5 | | -6 | | | |
		Min	Max	Min	Max		
$\overline{CAS}$ setup time (CBR refresh cycle)	t_{CSR}	5	—	5	—	ns	
$\overline{CAS}$ hold time (CBR refresh cycle)	t_{CHR}	8	—	10	—	ns	
$\overline{WE}$ setup time (CBR refresh cycle)	t_{WRP}	0	—	0	—	ns	
$\overline{WE}$ hold time (CBR refresh cycle)	t_{WRH}	8	—	10	—	ns	
$\overline{RAS}$ precharge to $\overline{CAS}$ hold time	t_{RPC}	5	—	5	—	ns	

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EDO Page Mode Cycle

Parameter	Symbol	HM5164405F/HM5165405F				Unit	Notes
		-5		-6			
		Min	Max	Min	Max		
EDO page mode cycle time	t_{HPC}	20	—	25	—	ns	20
EDO page mode $\overline{RAS}$ pulse width	t_{RASP}	—	100000	—	100000	ns	16
Access time from $\overline{CAS}$ precharge	t_{CPA}	—	28	—	35	ns	9, 17
$\overline{RAS}$ hold time from $\overline{CAS}$ precharge	t_{CPRH}	28	—	35	—	ns	
Output data hold time from $\overline{CAS}$ low	t_{DOH}	3	—	3	—	ns	9, 22
$\overline{CAS}$ hold time referred $\overline{OE}$	t_{COL}	8	—	10	—	ns	
$\overline{CAS}$ to $\overline{OE}$ setup time	t_{COP}	5	—	5	—	ns	
Read command hold time from $\overline{CAS}$ precharge	t_{RCHC}	28	—	35	—	ns	
Write pulse width during $\overline{CAS}$ precharge	t_{WPE}	8	—	10	—	ns	
$\overline{OE}$ precharge time	t_{OEP}	8	—	10	—	ns	

EDO Page Mode Read-Modify-Write Cycle

Parameter	Symbol	HM5164405F/HM5165405F				Unit	Notes
		-5		-6			
		Min	Max	Min	Max		
EDO page mode read-modify-write cycle time	t_{HPRWC}	57	—	68	—	ns	
$\overline{WE}$ delay time from $\overline{CAS}$ precharge	t_{CPW}	45	—	54	—	ns	14

Refresh (HM5164405F Series)

Parameter	Symbol	Max	Unit	Notes
Refresh period	t_{REF}	64	ms	8192 cycles

Refresh (HM5165405F Series)

Parameter	Symbol	Max	Unit	Notes
Refresh period	t_{REF}	64	ms	4096 cycles

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Self Refresh Mode (L-version)

| Parameter | Symbol | HM5164405FL/HM5165405FL | | | | Unit | Notes |
| | | -5 | | -6 | | | |
		Min	Max	Min	Max		
$\overline{RAS}$ pulse width (self refresh)	t_{RASS}	100	—	100	—	µs	25
$\overline{RAS}$ precharge time (self refresh)	t_{RPS}	90	—	110	—	ns	25
$\overline{CAS}$ hold time (self refresh)	t_{CHS}	−50	—	−50	—	ns	

Notes: 1. AC measurements assume t_T = 2 ns.

2. An initial pause of 200 µs is required after power up followed by a minimum of eight initialization cycles (any combination of cycles containing $\overline{RAS}$-only refresh or $\overline{CAS}$-before-$\overline{RAS}$ refresh).

3. Operation with the t_{RCD} (max) limit insures that t_{RAC} (max) can be met, t_{RCD} (max) is specified as a reference point only; if t_{RCD} is greater than the specified t_{RCD} (max) limit, than the access time is controlled exclusively by t_{CAC}.

4. Operation with the t_{RAD} (max) limit insures that t_{RAC} (max) can be met, t_{RAD} (max) is specified as a reference point only; if t_{RAD} is greater than the specified t_{RAD} (max) limit, then access time is controlled exclusively by t_{AA}.

5. Either t_{OED} or t_{CDD} must be satisfied.

6. Either t_{DZO} or t_{DZC} must be satisfied.

7. V_{IH} (min) and V_{IL} (max) are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} (min) and V_{IL} (max).

8. Assumes that $t_{RCD} \le t_{RCD}$ (max) and $t_{RAD} \le t_{RAD}$ (max). If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.

9. Measured with a load circuit equivalent to 1 TTL loads and 100 pF.

10. Assumes that $t_{RCD} \ge t_{RCD}$ (max) and $t_{RCD} + t_{CAC}$ (max) $\ge t_{RAD} + t_{AA}$ (max).

11. Assumes that $t_{RAD} \ge t_{RAD}$ (max) and $t_{RCD} + t_{CAC}$ (max) $\le t_{RAD} + t_{AA}$ (max).

12. Either t_{RCH} or t_{RRH} must be satisfied for a read cycles.

13. t_{OFF} (max), t_{OEZ} (max), t_{WEZ} (max) and t_{OFR} (max) define the time at which the outputs achieve the open circuit condition and are not referred to output voltage levels.

14. t_{WCS}, t_{RWD}, t_{CWD}, t_{AWD} and t_{CPW} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only; if $t_{WCS} \ge t_{WCS}$ (min), the cycle is an early write cycle and the data out pin will remain open circuit (high impedance) throughout the entire cycle; if $t_{RWD} \ge t_{RWD}$ (min), $t_{CWD} \ge t_{CWD}$ (min), and $t_{AWD} \ge t_{AWD}$ (min), or $t_{CWD} \ge t_{CWD}$ (min), $t_{AWD} \ge t_{AWD}$ (min) and $t_{CPW} \ge t_{CPW}$ (min), the cycle is a read-modify-write and the data output will contain data read from the selected cell; if neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.

15. t_{DS} and t_{DH} are referred to $\overline{CAS}$ leading edge in early write cycles and to $\overline{WE}$ leading edge in delayed write or read-modify-write cycles.

16. t_{RASP} defines $\overline{RAS}$ pulse width in EDO page mode cycles.

17. Access time is determined by the longest among t_{AA}, t_{CAC} and t_{CPA}.

18. In delayed write or read-modify-write cycles, $\overline{OE}$ must disable output buffer prior to applying data to the device.

19. When output buffers are enabled once, sustain the low impedance state until valid data is obtained. When output buffer is turned on and off within a very short time, generally it causes large V_{CC}/V_{SS} line noise, which causes to degrade V_{IH} min/V_{IL} max level.

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20. t_{HPC} (min) can be achieved during a series of EDO page mode write cycles or EDO page mode read cycles. If both write and read operation are mixed in a EDO page mode $\overline{RAS}$ cycle (EDO page mode mix cycle (1), (2)), minimum value of $\overline{CAS}$ cycle ($t_{CAS} + t_{CP} + 2\ t_T$) becomes greater than the specified t_{HPC} (min) value. The value of $\overline{CAS}$ cycle time of mixed EDO page mode is shown in EDO page mode mix cycle (1) and (2).

21. Data output turns off and becomes high impedance from later rising edge of $\overline{RAS}$ and $\overline{CAS}$. Hold time and turn off time are specified by the timing specifications of later rising edge of $\overline{RAS}$ and $\overline{CAS}$ between t_{OHR} and t_{OH} and between t_{OFR} and t_{OFF}.

22. t_{DOH} defines the time at which the output level go cross. $V_{OL} = 0.8$ V, $V_{OH} = 2.0$ V of output timing reference level.

23. Before and after self refresh mode, execute CBR refresh to all refresh addresses in or within 64 ms period on the condition a and b below.

    a. Enter self refresh mode within 15.6 µs after either burst refresh or distributed refresh at equal interval to all refresh addresses are completed.

    b. Start burst refresh or distributed refresh at equal interval to all refresh addresses within 15.6µs after exiting from self refresh mode.

24. In case of entering from $\overline{RAS}$-only-refresh, it is necessary to execute CBR refresh before and after self refresh mode according as note 23.

25 At $t_{RASS} > 100$ µs, self refresh mode is activated, and not activated at $t_{RASS} < 10$ µs. It is undefined within the range of 10 µs $\leq t_{RASS} \leq 100$ µs. For $t_{RASS} \geq 10$ µs, it is necessary to satisfy t_{RPS}.

26. XXX: H or L (H: V_{IH} (min) $\leq V_{IN} \leq V_{IH}$ (max), L: V_{IL} (min) $\leq V_{IN} \leq V_{IL}$ (max))

    ///////: Invalid Dout

    When the address, clock and input pins are not described on timing waveforms, their pins must be applied V_{IH} or V_{IL}.

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Timing Waveforms*[26]

Read Cycle
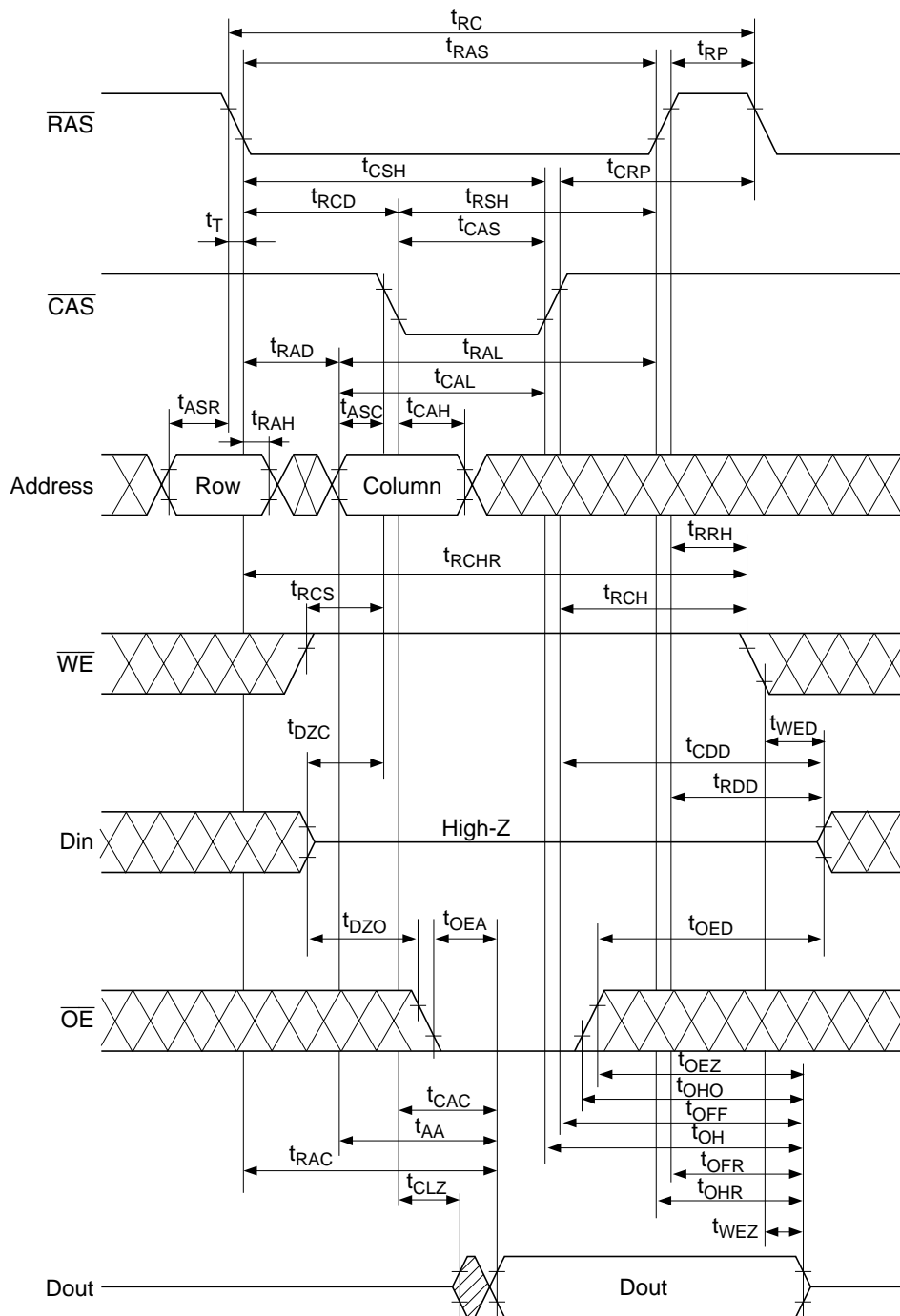
Early Write Cycle

$$* \quad t_{WCS} \geqq t_{WCS}(min)$$
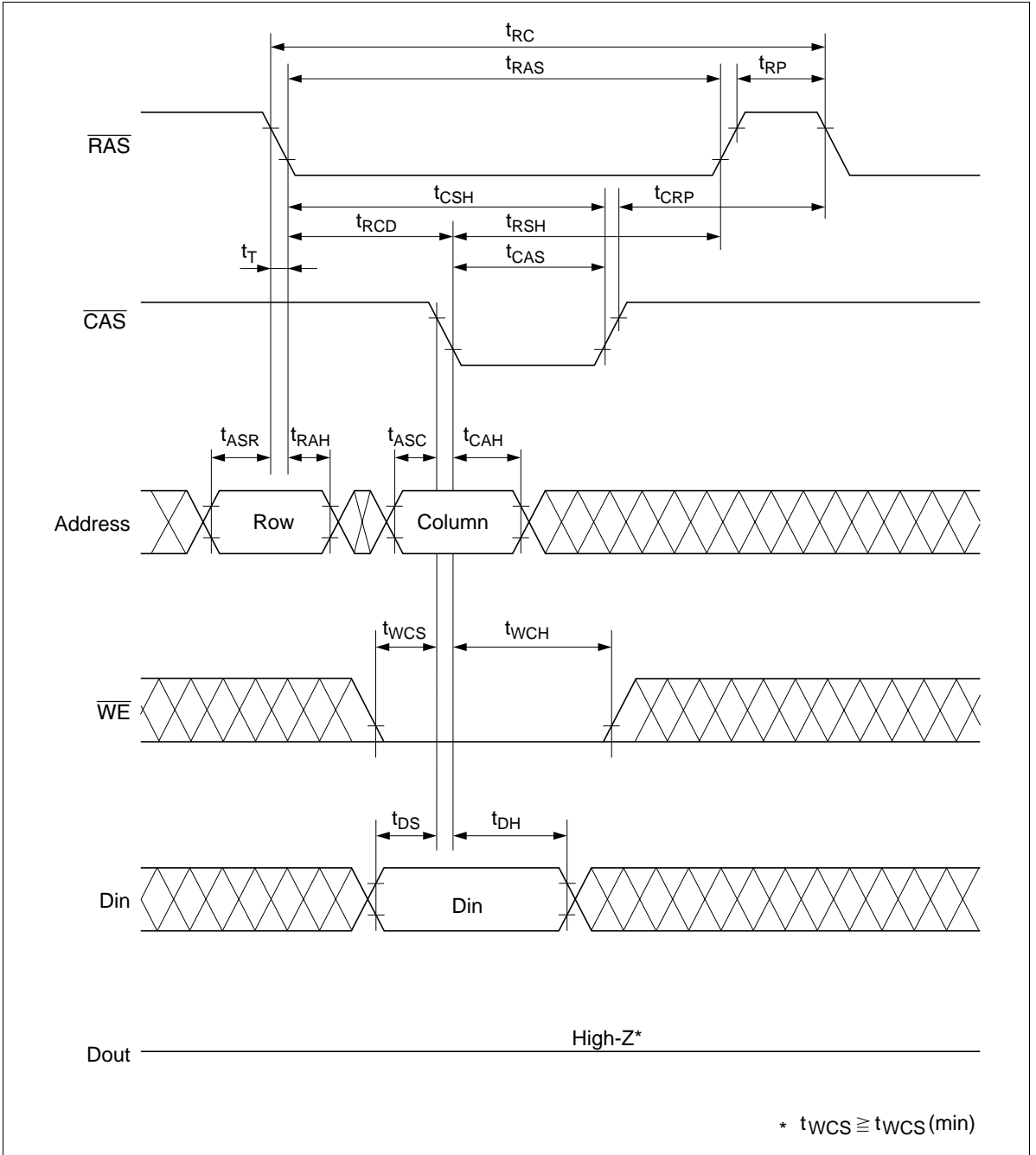
Delayed Write Cycle*[18]
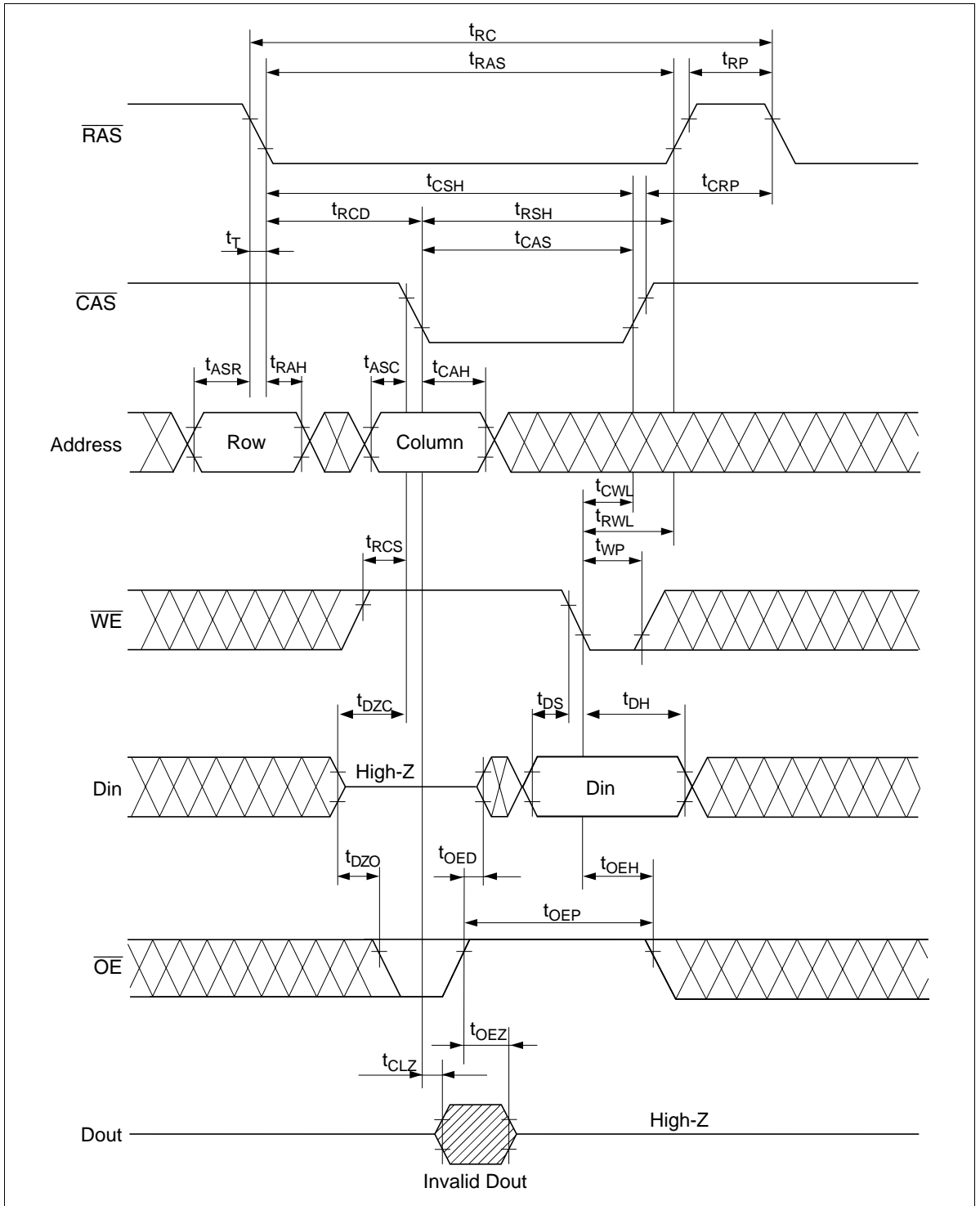
Read-Modify-Write Cycle*[18]
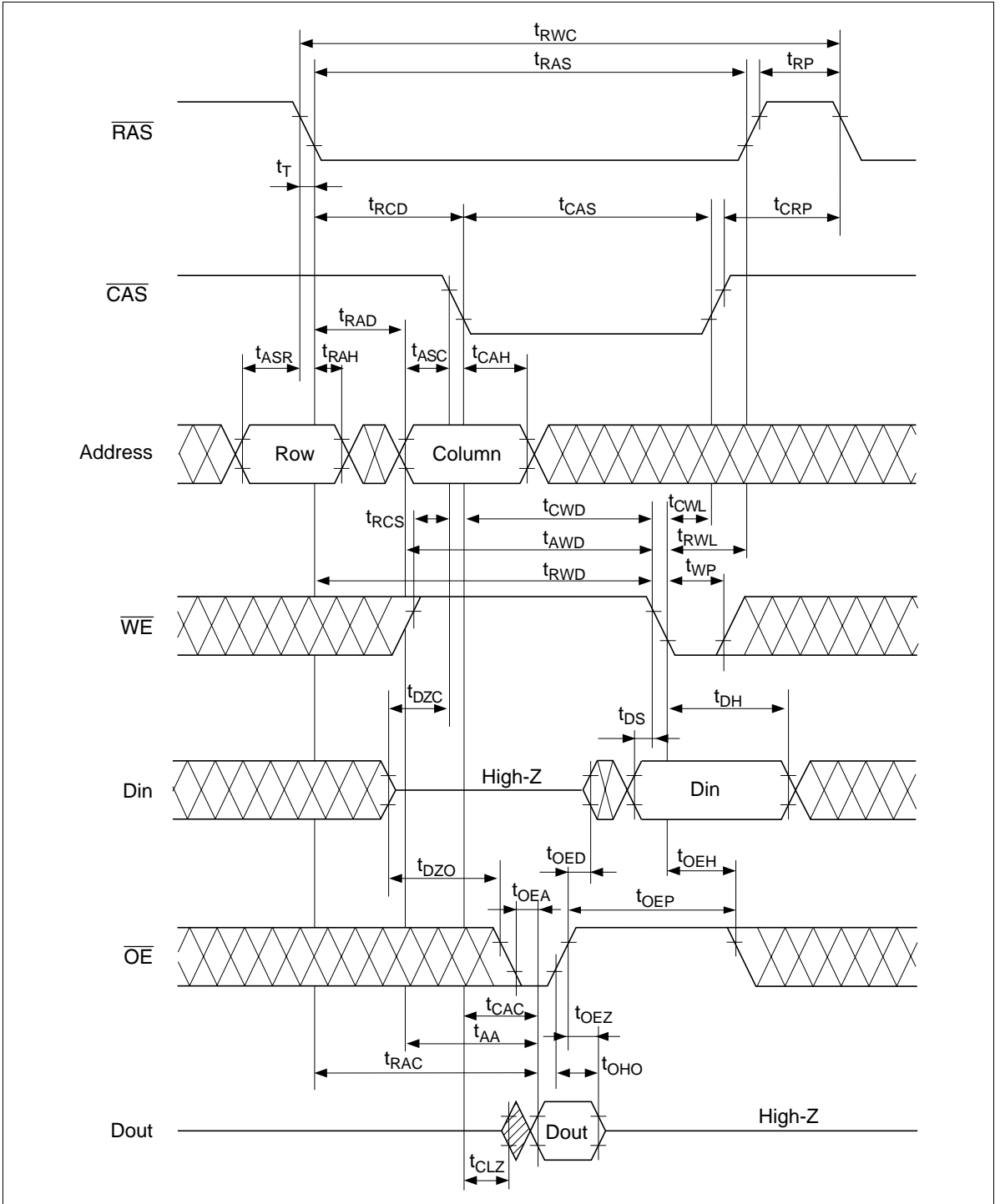
$\overline{\text{RAS}}$-Only Refresh Cycle
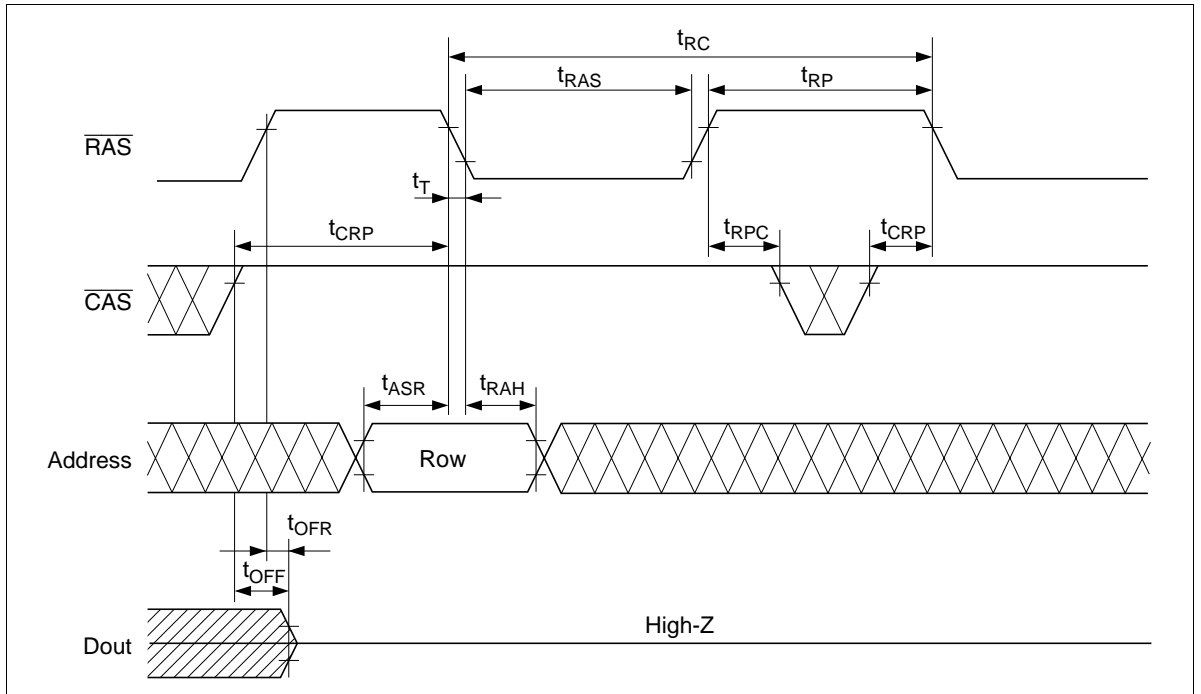
$\overline{\text{CAS}}$-Before-$\overline{\text{RAS}}$ Refresh Cycle

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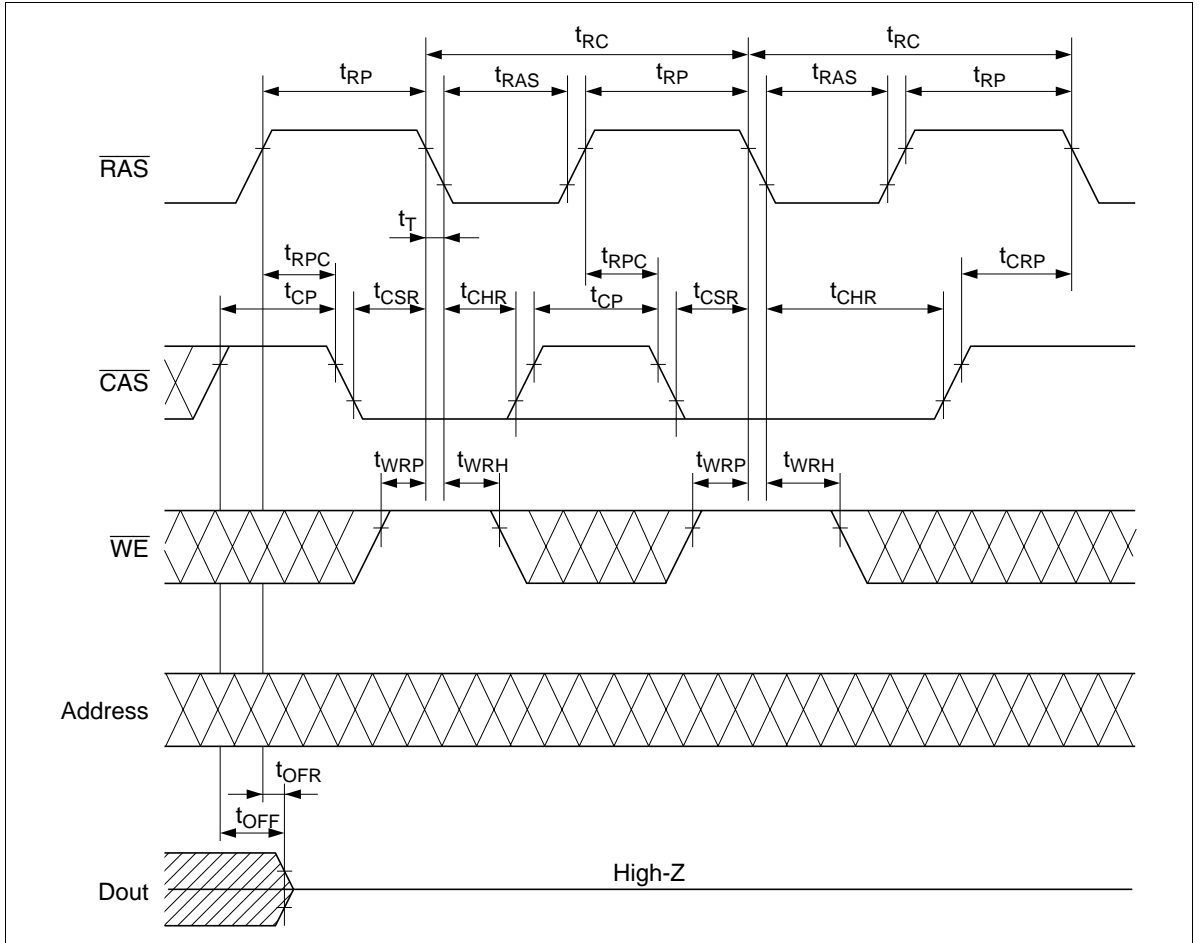
Hidden Refresh Cycle
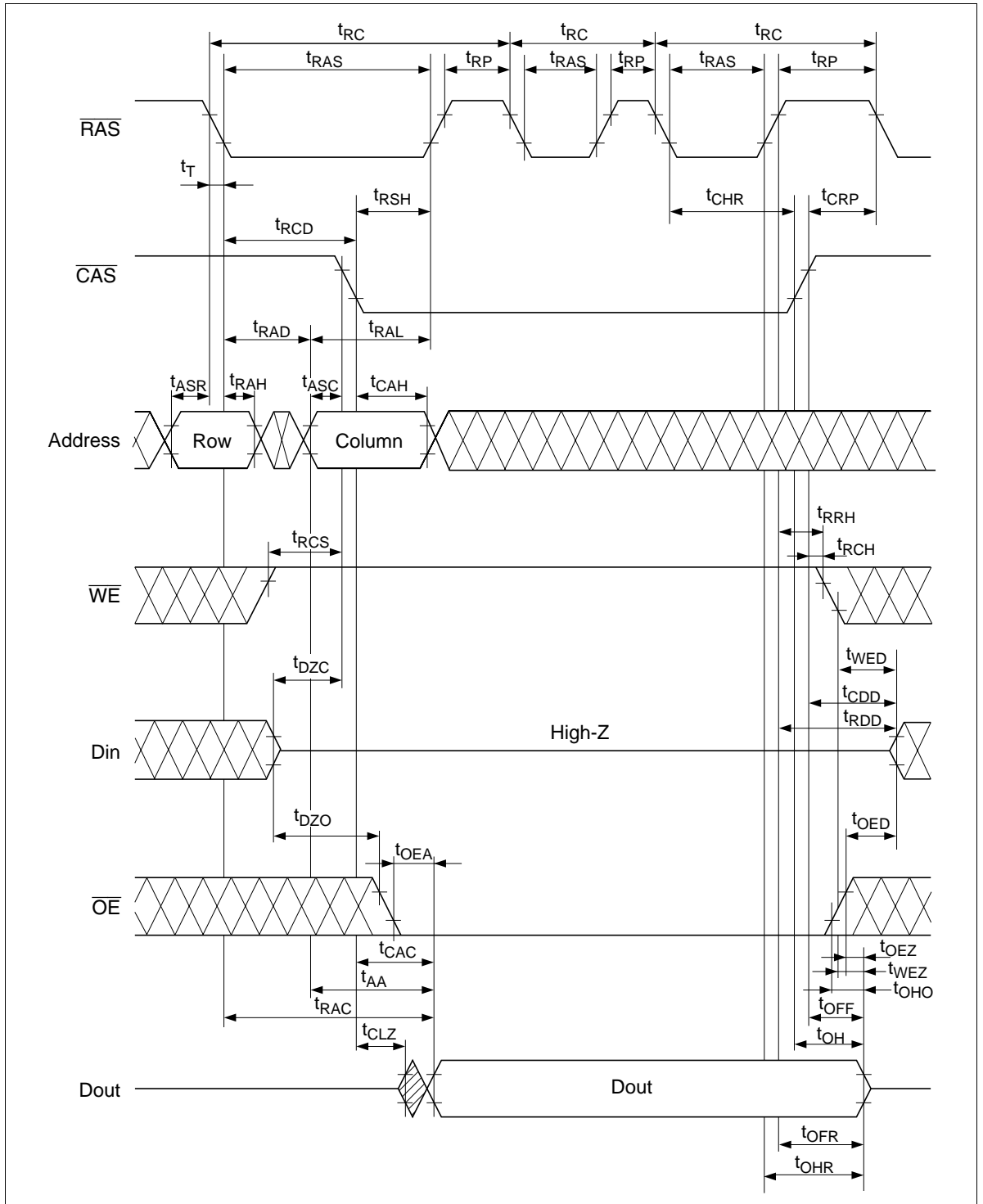
EDO Page Mode Read Cycle (1)

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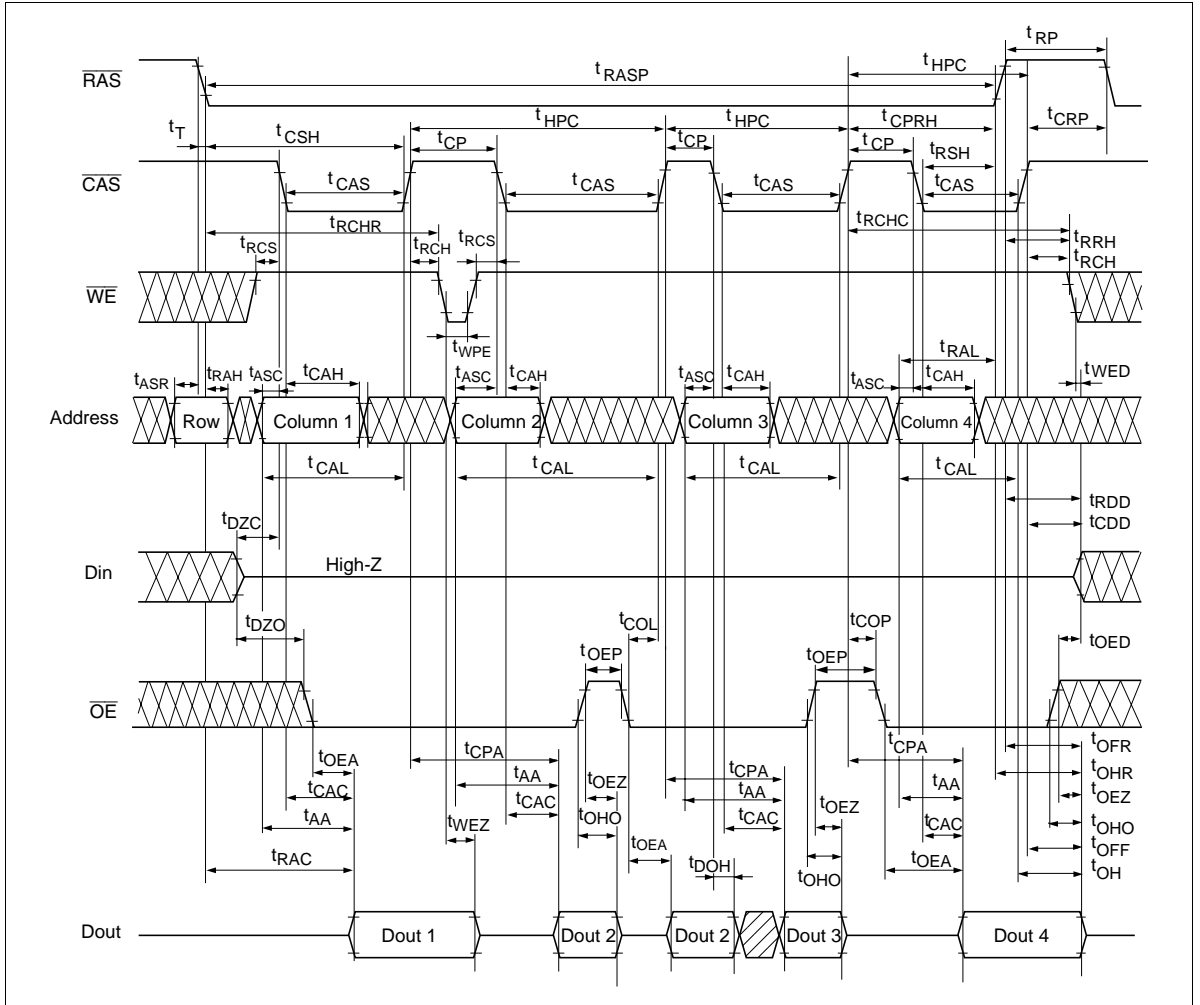
EDO Page Mode Read Cycle (2)
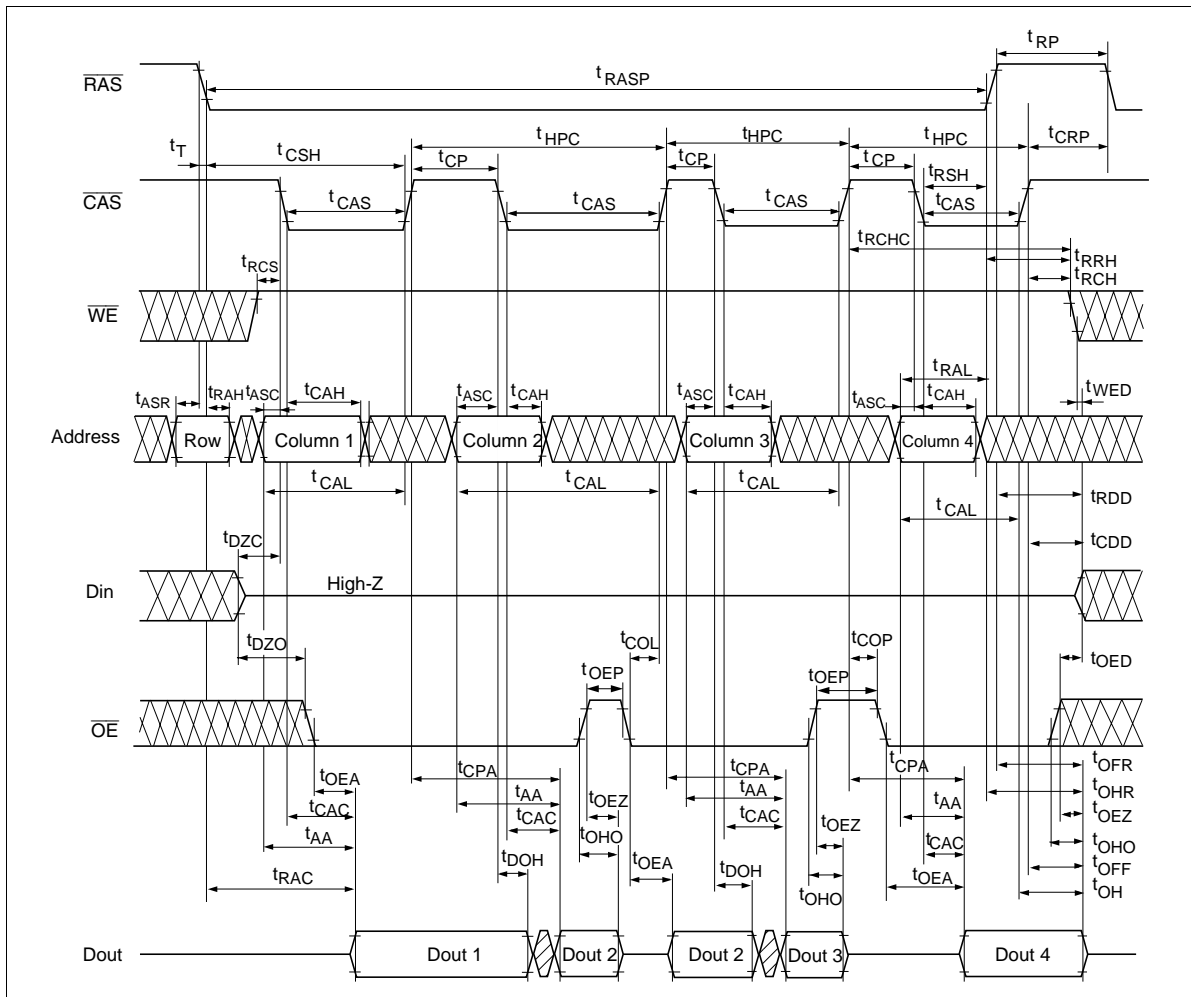
EDO Page Mode Early Write Cycle

$$* \quad t_{WCS} \geqq t_{WCS}(min)$$
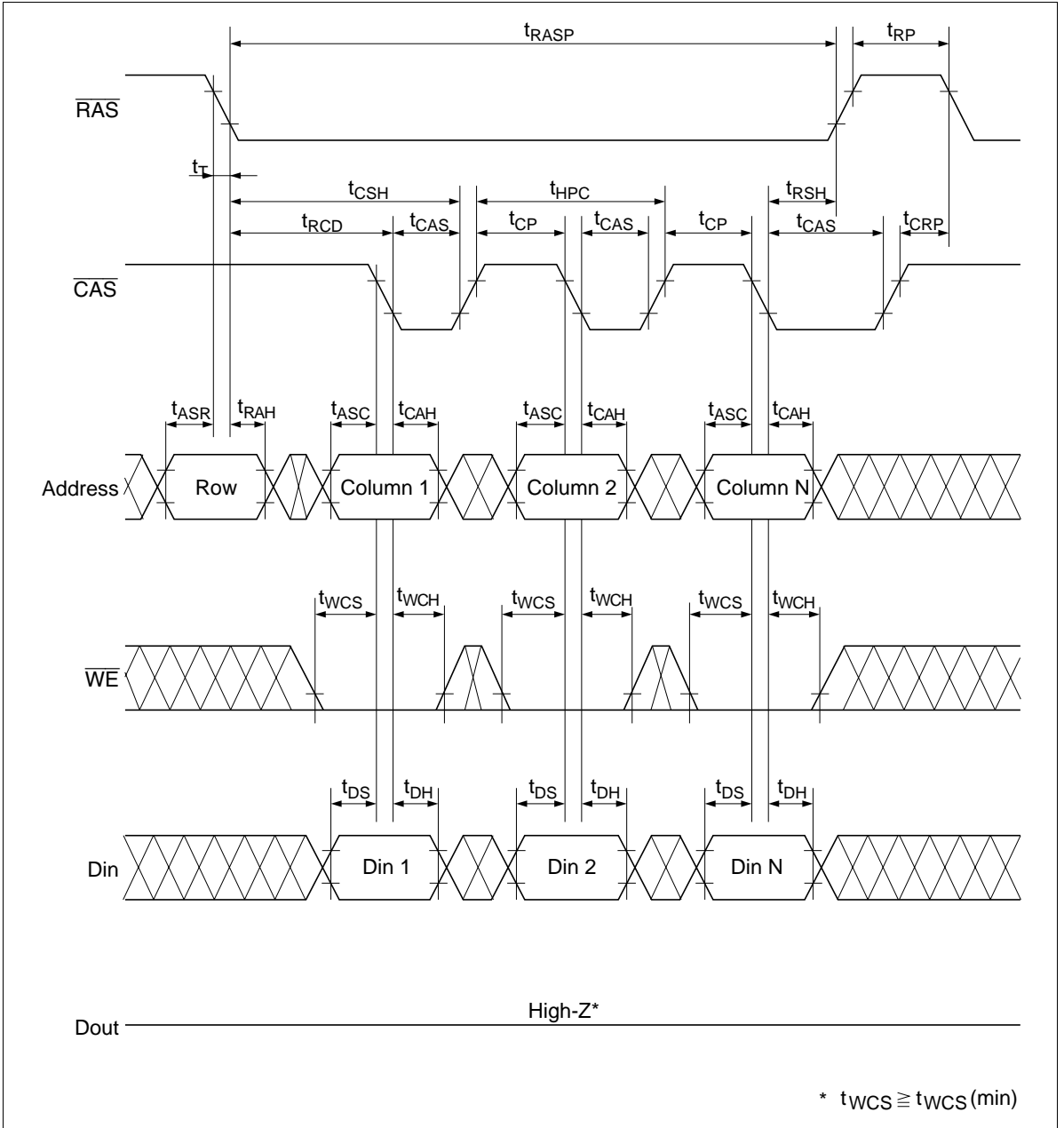
EDO Page Mode Delayed Write Cycle[18]
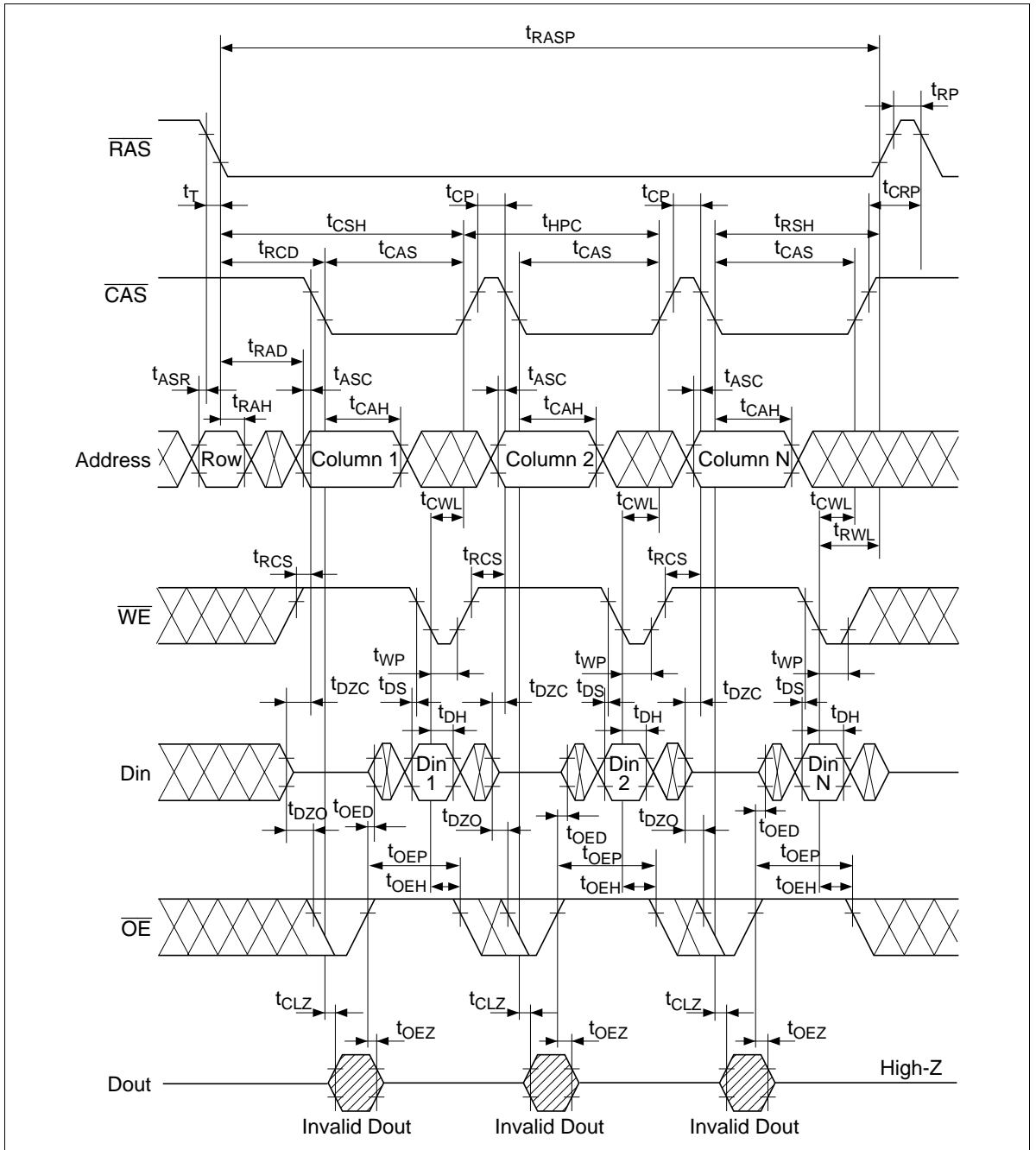
EDO Page Mode Read-Modify-Write Cycle*[18]

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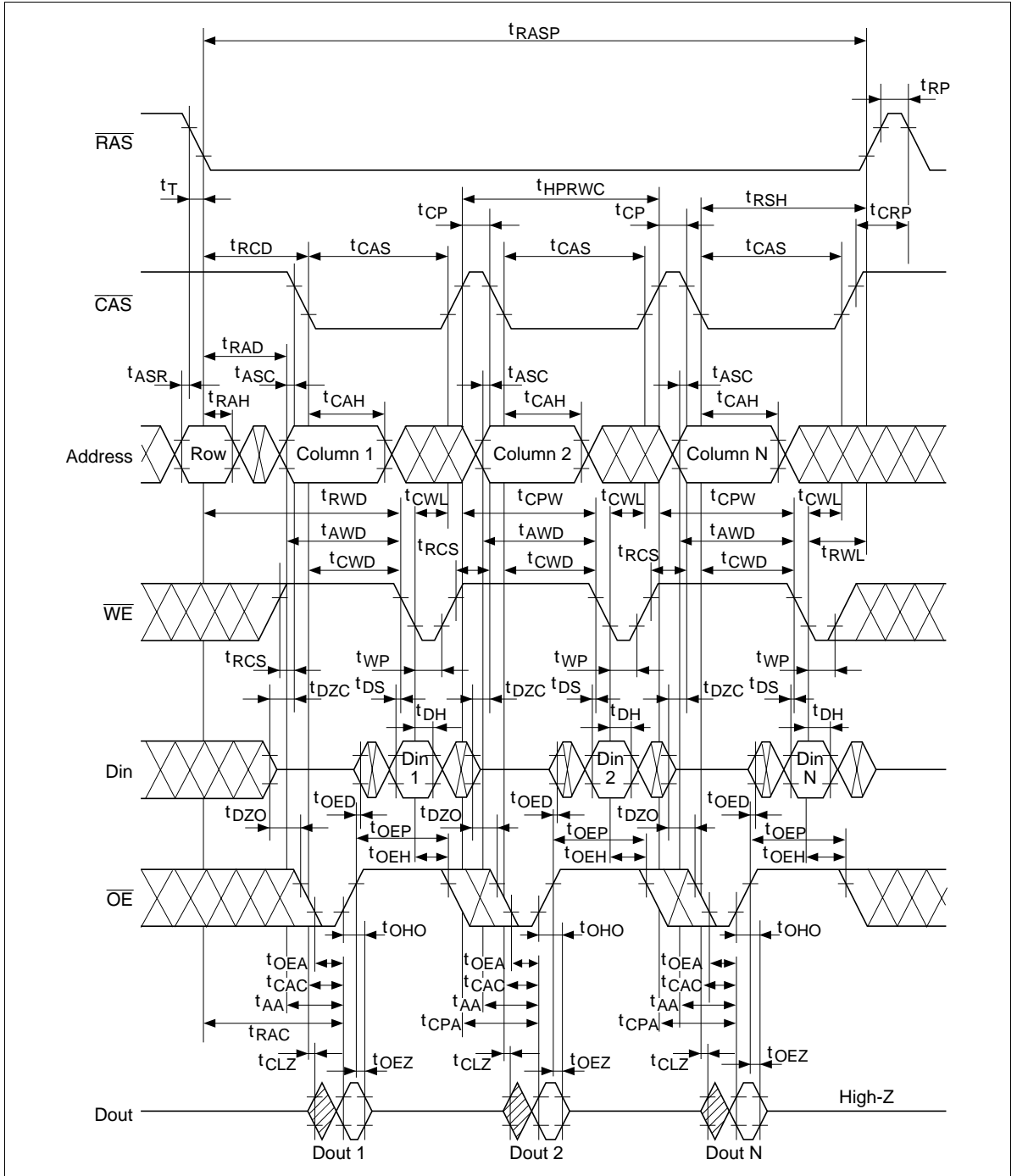
EDO Page Mode Mix Cycle (1)*[20]
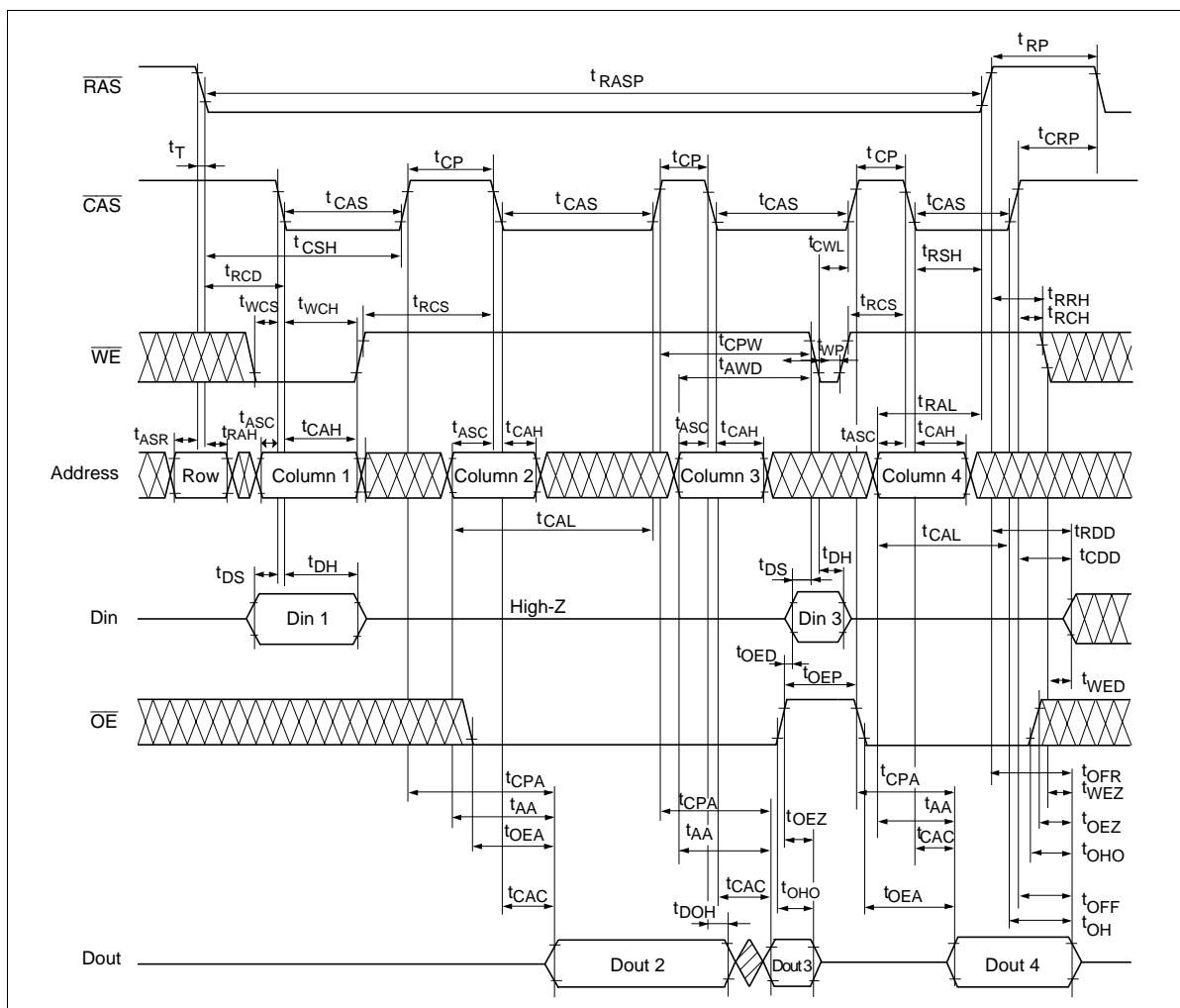
EDO Page Mode Mix Cycle (2) *[20]
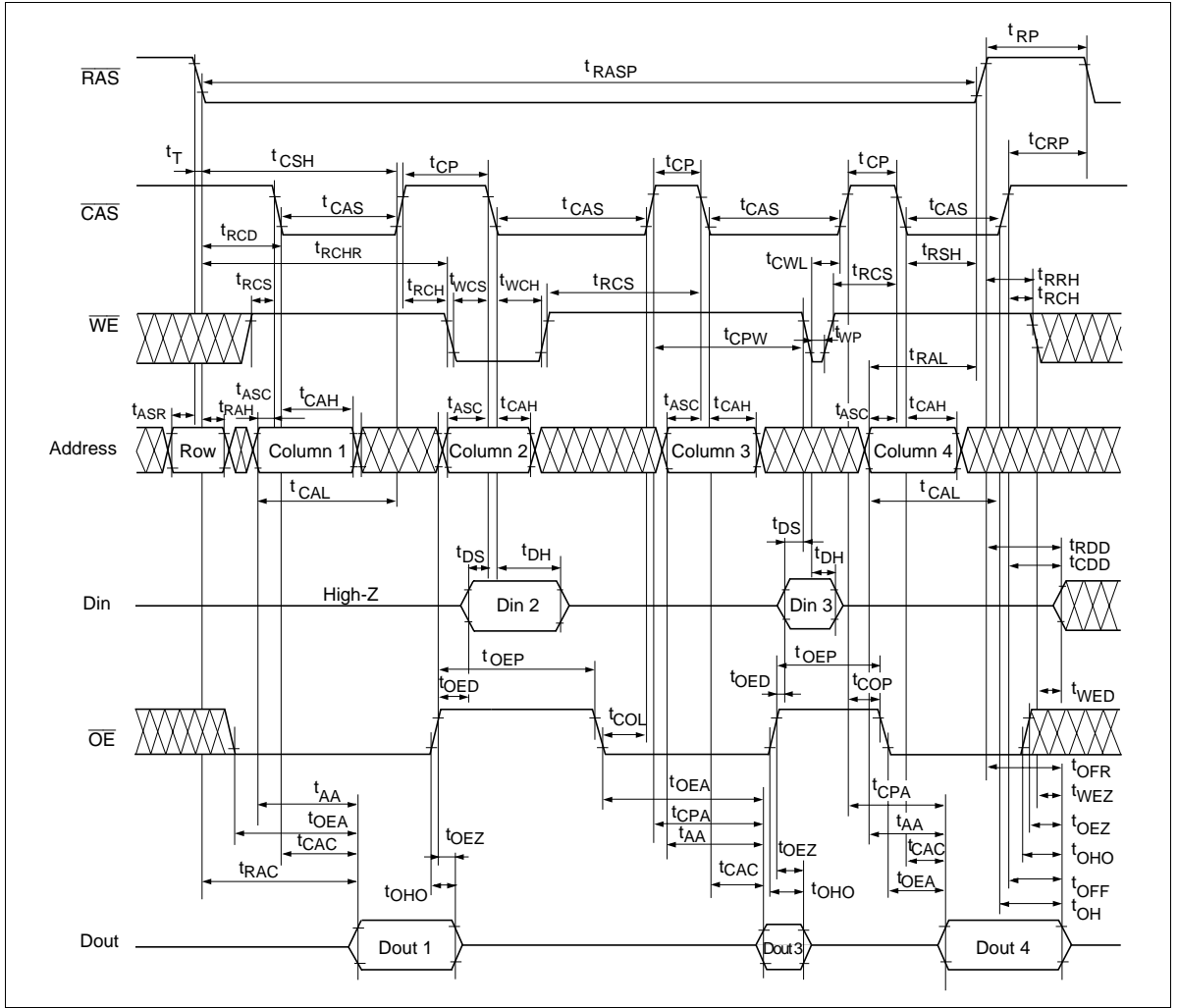
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Self Refresh Cycle (L-version)* [23, 24, 25]
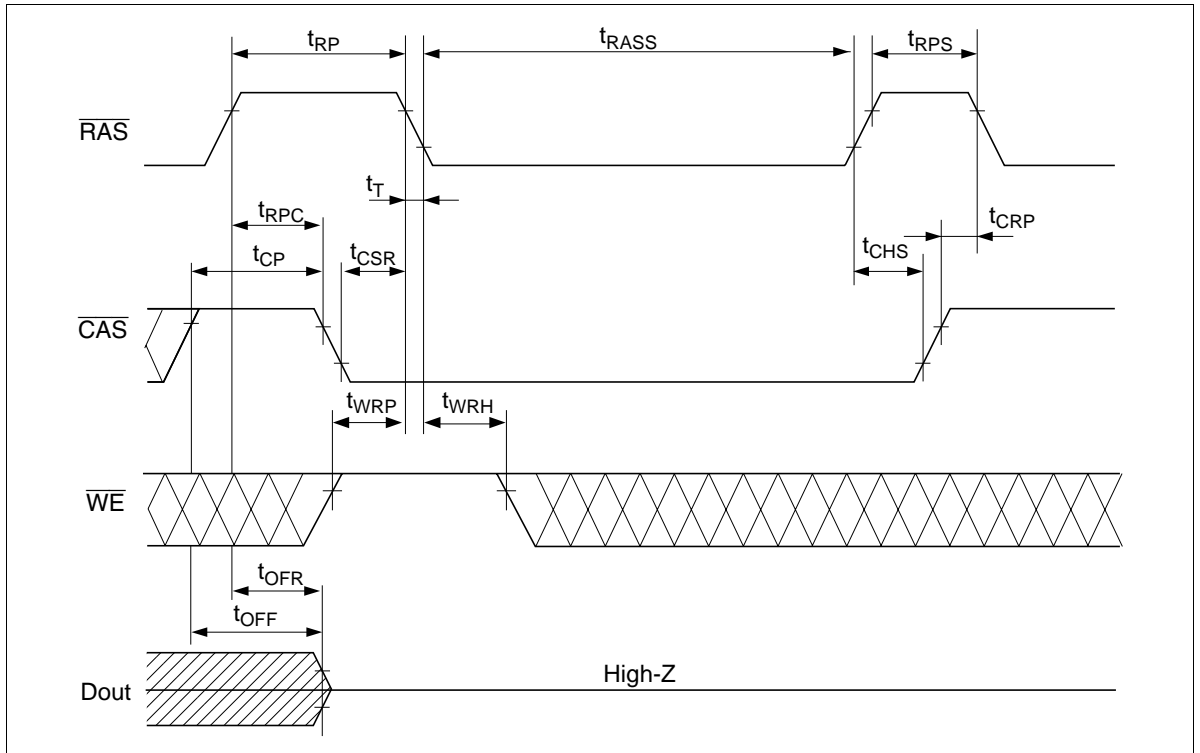
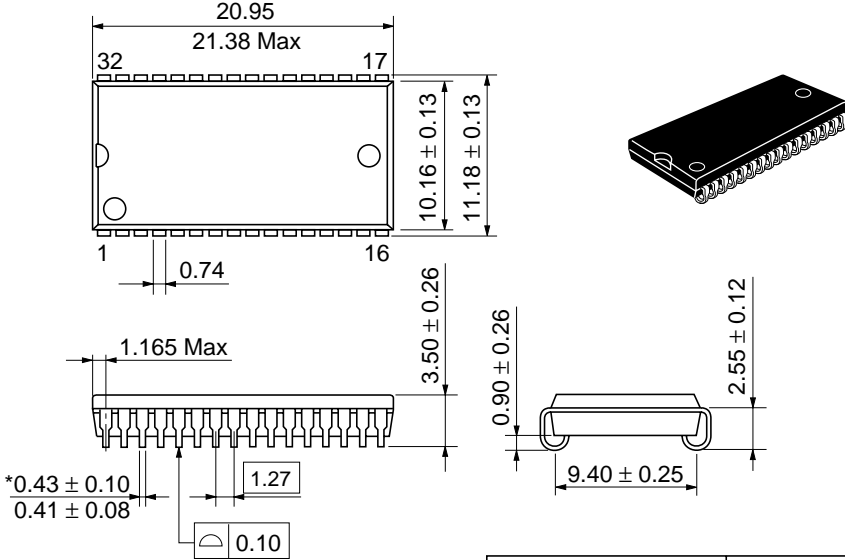# HM5164405F Series, HM5165405F Series

Package Dimensions

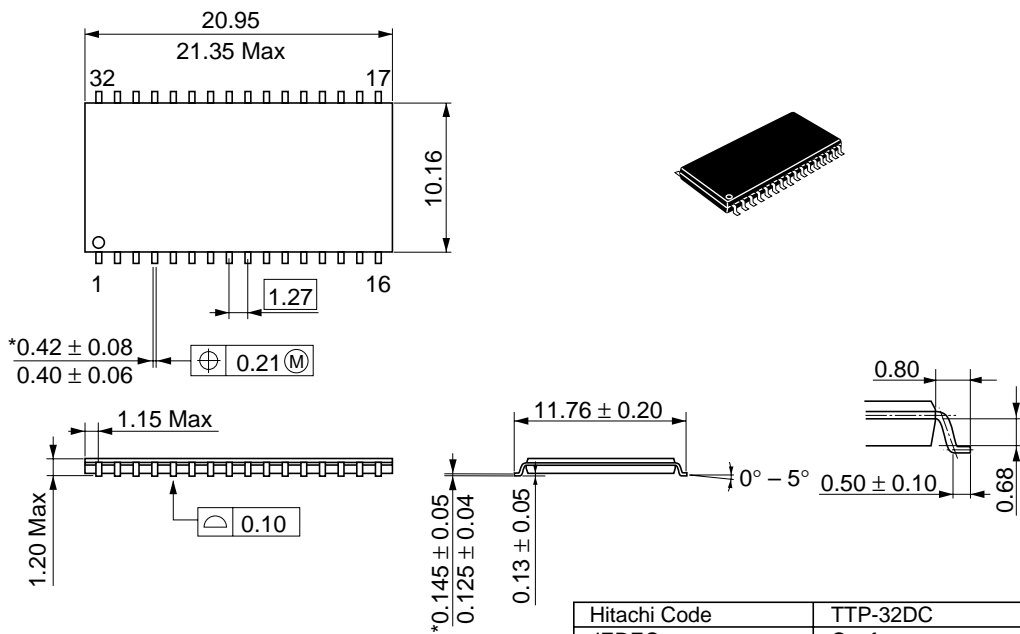**HM5164405FJ/FLJ Series**
HM5165405FJ/FLJ Series (CP-32DC)

Unit: mm

Hitachi Code	CP-32DC
JEDEC	—
EIAJ	Conforms
Weight (reference value)	1.2 g

*Dimension including the plating thickness
Base material dimension

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HM5164405FTT/FLTT Series

HM5165405FTT/FLTT Series (TTP-32DC)

Unit: mm

20.95
21.35 Max

32   17

10.16

1   16

1.27

*0.42 ± 0.08 / 0.40 ± 0.06

⊕ 0.21 Ⓜ

1.15 Max

1.20 Max

△ 0.10

11.76 ± 0.20

*0.145 ± 0.05 / 0.125 ± 0.04

0.13 ± 0.05

0° − 5°

0.50 ± 0.10

0.80

0.68

*Dimension including the plating thickness / Base material dimension

Hitachi Code	TTP-32DC
JEDEC	Conforms
EIAJ	—
Weight (reference value)	0.51 g

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Revision Record

Rev.	Date	Contents of Modification	Drawn by	Approved by
0.0	May. 25, 1999	Initial issue	M. Kawamura	M. Mishima
1.0	Oct. 5, 1999	Features: Change of Power dissipation 　　　　Standby (L-version) max: TBD to 1.1 mW DC Characteristics 　　I_{CC2} (L-version) max: TBD/TBD to 300/300 μA 　　I_{CC10} (L-version) max: TBD/TBD to 1/1 mA 　　I_{CC11} (L-version) max: TBD/TBD to 500/500 μA	M. Kawamura	Y. Kasama
2.0	Nov. 30, 1999	DC Characteristics 　　I_{CC10} (L-version) max: 1/1 mA to 1.2/1.2 mA		